

Differential reflectance spectroscopy on molecular layers: experimental aspects

Laurent Nony

▶ To cite this version:

Laurent Nony. Differential reflectance spectroscopy on molecular layers: experimental aspects. Doctoral. France. 2019. cel-02083155

HAL Id: cel-02083155 https://hal.archives-ouvertes.fr/cel-02083155

Submitted on 28 Mar 2019

HAL is a multi-disciplinary open access archive for the deposit and dissemination of scientific research documents, whether they are published or not. The documents may come from teaching and research institutions in France or abroad, or from public or private research centers. L'archive ouverte pluridisciplinaire **HAL**, est destinée au dépôt et à la diffusion de documents scientifiques de niveau recherche, publiés ou non, émanant des établissements d'enseignement et de recherche français ou étrangers, des laboratoires publics ou privés.



Institut Matériaux Microélectronique Nanosciences Provence

Spectroscopie de réflectivité différentielle sur des couches moléculaires: aspects expérimentaux

Laurent Nony

laurent.nony@im2np.fr

Aix-Marseille Université, CNRS, IM2NP UMR 7334, 13397, Marseille, France

Ecole thématique « Couplage entre les techniques de microscopies à sondes locales et l'optique » 18-19 Mars 2019, Carry le Rouet



Research topics of the Nanostructuration group















2

Towards optical properties

Motivation: completing structural measurements with optical spectroscopy structure ↔ property



- *in situ* (UHV) & real time UV-vis absorption spectra
- sensitivity ~ 0.1% (~ sub-ML)













Outline

- I. Reminder, context of DRS on molecular films
- II. Tutorial video: experimental aspects of DRS on molecular films
- III. Connection to the structural properties of the molecular films by nc-AFM
- IV. DRS functionnal for fitting the DR spectra
- V. Conclusion List of publications















I. Reminder, context of DRS on molecular films

dutorial video: experimental aspects of DRS on nolecular films

Sonnection to the structural properties of the molecular ms by nc-AFM

DRS functionnal for fitting the DR spectra

Conclusion of publications













• Differential Reflectance Spectroscopy:













- Differential Reflectance Spectroscopy:
 - The combination between both Snell law, Fresnel equations and a linearization procedure¹ (d₁<<l) yields to the so-called *Mc Intyre's approach* to DRS:

$$\mathrm{DRS}^{(s)} = \frac{R(d_1) - R(0)}{R(0)} = \frac{|\widetilde{r}(d_1)|^2 - |\widetilde{r}(0)|^2}{|\widetilde{r}(0)|^2} = \frac{8\pi d_1 \cos \theta_0}{\lambda (n_2^2 - 1)} \mathrm{Im}\{\widetilde{n}_1^2\}$$

- Relates to the optical absorption of the molecular film
- Goal: quantitative determination of the molecular film's dielectric function ε(λ) (or its refractive index: n(λ) = √ε(λ))

¹J.D.E.McIntyre et al., Surf.Sci. 24, 417 (1971)













Franck Bocquet's lecture on « Theoretical aspects of • DRS on molecular films »:



UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)

UNIVERSITÉ

 Franck Bocquet's lecture on « Theoretical aspects of DRS on molecular films »:





Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)









 Franck Bocquet's lecture on « Theoretical aspects of DRS on molecular films »:





Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)









 Ultimate methodology to extract the dielectric function : DRS spectrum















Reminder, context of DRS on molecular films

II. Tutorial video: experimental aspects of DRS on molecular films

Sonnection to the structural properties of the molecular ims by nc-AFM

DRS functionnal for fitting the DR spectra

Conclusion of publications













Tutorial video: experimental aspects of DRS¹³

- Part 1: UHV setup for DRS and non-contact AFM
- Part 2: Preparing and introducing molecules
- **Part 3:** Preparing and introducing samples
- **Part 4:** Calibrating the molecular flux
- Part 5: Annealing the sample
- Part 6: DRS setup
- **Part 7:** Checking the optical alignment and the stability of the detection
- Part 8: DRS acquisition
- Part 9: Post-processing
- Part 10: Data analysis...













Tutorial video: experimental aspects of DRS

• The link to the video:

https://amubox.univ-amu.fr/s/4YRR2StjtGoaPGm













14



Reminder, context of DRS on molecular films

dutorial video: experimental aspects of DRS on nolecular films

III. Connection to the structural properties of the molecular films by nc-AFM

DRS functionnal for fitting the DR spectra

Conclusion of publications













Connection to the structural properties of the molecular films by nc-AFM

• Examplary case : curcuminoid chromophores



Large crystallites of equivalent domains

Orientations of ML @ +/-45°w.r.t. <100> direction





Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)









17

Connection to the structural properties of the molecular films by nc-AFM

• Examplary case : curcuminoid chromophores

Zoom on a domain:

- Molecular rows match substrate's <110> polar lines
- Apparent height : 4.0 Å
- Atomic resolution on KCI (traces in FFT)







Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)







S







Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)









Outline

Reminder, context of DRS on molecular films

Jutorial video: experimental aspects of DRS on molecular films

Sonnection to the structural properties of the molecular ms by nc-AFM

IV. DRS functionnal for fitting the DR spectra

Conclusion of publications













- Beyond Mc Intyre's approach...
 - Back to optics basics...

DRS =
$$\frac{R(d_1) - R(0)}{R(0)} = \frac{|\widetilde{r}(d_1)|^2 - |\widetilde{r}(0)|^2}{|\widetilde{r}(0)|^2}$$
(Equ.0)











22 **DRS** functionnal for fitting the DR spectra Multi-layers = Stratified medium: • Vacuum 0 (n_=1) Uniaxial material approximation (x,y,z geom. accordingly with Ad-layer (n₁): d₁ 1 anisotropic cristallographic axes) z axis = optic axis Ad-layer (n₂): d₂ 2 Ż anisotropic Dielectric tensor of the jth layer: **F**^{+,} (s,p) Ad-layer (n_j): d_j anisotropic **-** -, (s,p) $\widetilde{\epsilon}_{j}^{\perp}(\lambda) = 0$ j $\overline{\overline{\epsilon}}_j =$ (Equ.1) ... Ad-layer (n_N): d_N Ν anisotropic Hence, $\overline{\overline{n}}_j = \Re\{\overline{\overline{n}}_j\} + i\Im\{\overline{\overline{n}}_j\} = \sqrt{\overline{\epsilon}_j}$. <010> → <100> "Semi-infinite" transparent E^{t,s} <001> substrate (n_): $d_{a} \rightarrow \infty$ Institut Matériaux Microélectronique Nanosciences Provence Aix*Marseille Association UNIVERSITÉ ISEN Chrs

université

DE TOULON

UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)



23 DRS functionnal for fitting the DR spectra Multi-layers = Stratified medium: • E^{i,s} Vacuum $(n_{1}=1)$ Electric field may be split into s (y axis) and **p** (x,z axes) Ad-layer (n₁): d₁ 1 polarizations: anisotropic $\mathbf{E}^{\dagger} = \mathbf{E}^{\dagger,s} + \mathbf{E}^{\dagger,p}.$ Ad-layer (n₂): d₂ 2 Ż anisotropic (with $\dagger = i, r, \text{ or } t$) Thus: Ad-layer (n_i): d_j E^{+, (s,p)} anisotropic E⁺ **-**-, (s,p) j $\mathbf{E}^{\dagger,s} = E^{\dagger,y} \mathbf{e}_{y} e^{i[\omega t - k^{\dagger,x} x - k^{\dagger,z} z]}$ $\mathbf{E}^{\dagger,p} = \{E^{\dagger,x} \mathbf{e}_{x} + E^{\dagger,z} \mathbf{e}_{z}\} e^{i[\omega t - k^{\dagger,x} x - k^{\dagger,z} z]}$ Ad-layer (n_N): d_N N anisotropic <010> → <100> with $\mathbf{k}^{\dagger} = k^{\dagger,x}\mathbf{e}_{x} + k^{\dagger,y}\mathbf{e}_{y} + k^{\dagger,z}\mathbf{e}_{z}$ "Semi-infinite" transparent $\mathbf{E}^{t,s}$ <001> substrate (n.): d. $\rightarrow \infty$ Association ISEN Cnrs

Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)

Aix*Marseille université





- Multi-layers = Stratified medium:
 - Reflection coefficient:

$$r^{(s,p)}(d) = \frac{\|\mathbf{E}^{r,(s,p)}(d)\|}{\|\mathbf{E}^{i,(s,p)}\|}$$

Reflectance components:

 $R^{(s,p)}(d) = |r^{(s,p)}(d)|^2$

– DRS components:

DRS^(s,p)(d) =
$$\frac{R^{(s,p)}(d) - R^{(s,p)}(0)}{R^{(s,p)}(0)}$$

- Unpolarized DRS (*physical observable!*): $R^{u}(d) = [R^{s}(d) + R^{p}(d)]/2$ $DRS^{u}(d) = \frac{R^{u}(d) - R^{u}(0)}{R^{u}(0)}$ (Equ.2)











 Transfer matrix method (TMM)¹: 0 Vacuum Wave vector for a jth layer $(n_{1}=1)$ $\mathbf{k}_{i}^{(i,r)} = k_{i}^{(i,r),x} \mathbf{e}_{x} + k_{i}^{(+,-),z} \mathbf{e}_{z}$ Ad-layer (n₁): d₁ 1 anisotropic with (Snell's laws): $\begin{cases} k_j^{(i,r),x} = \frac{2\pi}{\lambda} n_0 \sin(\theta_0) \\ k_j^{(+,-),z} = \pm \frac{2\pi}{\lambda} \widetilde{n}_j(\lambda) \cos(\theta_j) \end{cases}$ Ad-layer (n₂): d₂ 2 Ż anisotropic Ad-layer (n_j): d_j E^{+, (s,p)} anisotropic E⁺ **-**-, (s,p) j For instance: Ad-layer (n_N): d_N $\mathbf{E}^{(+,-),s} = E^{(+,-),y} \mathbf{e}_{y} e^{i[\omega t - k^{(+,-),x} x - k^{(+,-),z} z]}$ Ν anisotropic <010> → <100> "Semi-infinite" transparent <001> substrate (n_s): d_s $\rightarrow \infty$ ¹R. Azzam and N. Bashara, Ellipsometry and Polarized Light (North Holland, Amsterdam, 1977). Institut Matériaux Microélectronique Nanosciences Provence Aix*Marseille Association UNIVERSITÉ ISEN CINIS INSTITUTS université UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN) DE TOULON

- Transfer matrix method (TMM)¹:
 - Boundary conditions (Maxwell equs.) at each interface yield inplane components of s and p polarizations:

$$\begin{pmatrix} E^{i,(x,y)} \\ E^{r,(x,y)} \end{pmatrix} = \frac{1}{2} \prod_{j=1}^{N} T_j \begin{pmatrix} \left[1 + \frac{\alpha_s}{\alpha_N}\right] E^{t,(x,y)} \\ \left[1 - \frac{\alpha_s}{\alpha_N}\right] E^{t,(x,y)} \end{pmatrix}$$

with the transfer matrix:

$$T_{j} = \frac{1}{2} \left(\begin{bmatrix} 1 + \frac{\alpha_{j}}{\alpha_{(j-1)}} \end{bmatrix} e^{i\beta_{j}} \begin{bmatrix} 1 - \frac{\alpha_{j}}{\alpha_{(j-1)}} \end{bmatrix} e^{-i\beta_{j}} \\ \begin{bmatrix} 1 - \frac{\alpha_{j}}{\alpha_{(j-1)}} \end{bmatrix} e^{i\beta_{j}} \begin{bmatrix} 1 + \frac{\alpha_{j}}{\alpha_{(j-1)}} \end{bmatrix} e^{-i\beta_{j}} \right)$$

Hence (removal of the transmitted component):



p polarization

¹R. Azzam and N. Bashara, Ellipsometry and Polarized Ligth (North Holland, Amsterdam, 1977).



Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)









- Transfer matrix method (TMM):
 - α_j and β_j coefficients:

• **s polarization case:** $\mathbf{E}^{(+,-),s} = E^{(+,-),y}\mathbf{e}_{y}$ (phase omitted) Perpendicular to the optic axis = *ordinary direction*

• *p* polarization case: $\mathbf{E}^{(+,-),p} = E^{(+,-),x}\mathbf{e}_x + E^{(+,-),z}\mathbf{e}_z$ (phase omitted) Parallel to the optic axis = *extraordinary direction*

$$\begin{cases} \alpha_j^e = \frac{\widetilde{n}_j^{\perp} \widetilde{n}_j^{\parallel}}{\sqrt{\widetilde{n}_j^{\parallel^2} - n_0^2 \sin^2(\theta_0)}} \\ \\ \beta_j^e = \frac{2\pi d_j}{\lambda} \frac{\widetilde{n}_j^{\perp}}{\alpha_j^e}. \end{cases}$$

(Equ.5)



Institut Matériaux Microélectronique Nanosciences Provence UMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)









• Summary: the combination between...













- But ε(λ) is still to be known as an input of the DRS functionnal...
 - In case of a homogeneous layer: Lorentz Oscillator Model (cf. Franck Bocquet's lecture):



$$\widetilde{\epsilon}_{\text{LOM}}(\lambda) = \epsilon^{\infty} + \sum_{j=1}^{3} \frac{f_j}{1 - \left(\frac{\lambda_j}{\lambda}\right)^2 + i\gamma_j\left(\frac{\lambda_j}{\lambda}\right)}$$

With:

- f_i = oscillator strength
- $\dot{\lambda}_i$ = absorption wavelength
- γ_i = peak width (relates to state lifetime)













- But ε(λ) is still to be known as an input of the DRS functionnal...
 - In case of an inhomogeneous layer: Effective Medium Theory¹ + Lorentz Oscillator Model:



¹B. J. C. Maxwell Garnet, Philos. Trans. R. Soc., A **203**, 385 (1904); V. Markel, J. Opt. Soc. Am. A **33**, 1244 (2016).









(Levenberg-Marquardt algorithm) are • The fits then performed on the experimental DR spectra with a Mathematica program and allow for the extraction of the dielectric function of the molecular layer, as well as an estimate of its thickness...



université



Institut Matériaux Microélectronique Nanosciences Provence JMR 7334, CNRS, Universités d'Aix-Marseille (AMU) et de Toulon (UTLN)

NSTITUTS

Outline

Reminder, context of DRS on molecular films

Jutorial video: experimental aspects of DRS on molecular films

Sonnection to the structural properties of the molecular ims by nc-AFM

DRS functionnal for fitting the DR spectra

V. Conclusion List of publications













Conclusion

- I. DRS on organic layers in UHV is an actual spectroscopic method to measure the UV-vis absorption spectrum of the organic layers
- II. Its experimental implementation is fairly simple
- III. Upon stability achievment, the method is sensitive to a fraction of ML
- IV. The quantitative extraction of the dielectric function of the molecular layers is tedious and rely on many approaches (stratified medium, uniaxial material, LOM, EMT...), whose relevance is to be estimated at best, and based on the molecular structure of the layers, the optical density of the molecules in solution...
- V. The interpretation of DR spectra without further information is useless : this can only be performed in connection with other inputs originating from other characterization methods









Acknowledgments



Nanostructuration group members @ IM2NP:

- Christian Loppacher
- Franck Bocquet
- Franck Para
- Sylvain Clair
- Luca Giovanelli
- Younal Ksari
- Jean-Marc Themlin



Colleagues @ CINaM:

- Thomas Léoni
- Conrad Becker
- Laurence Masson
- Romain Parret
- Frédéric Fagès
- Elena Zaborova











ISEN



Institut Matériaux Microélectronique Nanosciences Provence

Merci pour votre attention



Relier le fondamental aux applications dans nos domaines d'expertise

www.im2np.fr

List of publications of the « non-contact AFM » team (2008)

- « Analytical approach to the local contact potential difference on (100) ionic surfaces: implications for KPFM », F.Bocquet, L.Nony, Ch.Loppacher and Th.Glatzel, Phys. Rev. B 78, 035410 (2008).
- « Evolution of the Electronic Structure at the Interface between a Thin Film of Halogenated Phthalocyanine and the Ag(111) Surface », L.Giovanelli, P.Amsalem, J.M.Themlin, Y.Ksari, M.Abel, L.Nony, M.Koudia, F.Bondino, E.Magnano, M.Mossoyan-Deneux, and L.Porte, J. Phys. Chem. C 112, 8654-8661 (2008).
- « Interface dipole formation of different ZnPcCl8 phases on Ag(111) observed by Kelvin probe force microscopy », P.Milde, U.Zerweck, L.Eng, M.Abel, L.Giovanelli, L.Nony, M.Mossoyan, L.Porte, and Ch.Loppacher, Nanotechnology 19, 305501 (2008).
- « On the relevance of the atomic-scale contact potential difference by amplitude modulation- and frequency modulation-Kelvin probe force microscopy », L.Nony, F.Bocquet, Ch.Loppacher and Th.Glatzel, Nanotechnology 20, 264014 (2009).
- « Robust supramolecular network on Ag(111): hydrogen-bond enhancement through partial alcohol dehydrogenation », R.Pawlak, S.Clair, V.Oison, M.Abel, O.Ourdjini, N.A.A.Zwaneveld, D.Gigmes, D.Bertin, L.Nony and L.Porte, ChemPhysChem 10, 1032-1035 (2009).
- « Understanding the Atomic-Scale Contrast in Kelvin Probe Force Microscopy », L.Nony, A.S.Foster, F.Bocquet and Ch.Loppacher, Phys. Rev. Lett. 103, 036802 (2009).
- « Supramolecular Assemblies of 1,4-Benzene Diboronic Acid on KCI(001) », R.Pawlak, L.Nony, F.Bocquet, V.Oison, M.Sassi, J.-M.Debierre, Ch.Loppacher, and L.Porte, J. Phys. Chem. C 114, 9290–9295 (2010).
- « Polarization effects in noncontact atomic force microscopy: A key to model the tip-sample interaction above charged adatoms », F.Bocquet, L.Nony, and Ch.Loppacher, Phys. Rev. B 83, 035411 (2011).
- « Contribution of the numerical approach to Kelvin Probe Force Microscopy on the atomic-scale », L.Nony, A.S.Foster, F.Bocquet and Ch.Loppacher. Chapter in the book «Kelvin Probe Force Microscopy», (Eds. Sascha Sadewasser & Thilo Glatzel), Springer-Verlag Berlin Heidelberg (2011) (DOI 10.1007/978-3-642-22566-6)











List of publications of the « non-contact AFM » team (2008)

- *«FPGA-based programmable digital PLL with very high frequency resolution»*, J.Bouloc, L.Nony, C.Loppacher, W.Rahajandraibe, F.Bocquet, L.Zaid, Electronics, Circuits and Systems(ICECS), 2011 18th IEEE International Conference on, 2011, Page(s): 370 373.
- « Self-organized growth of molecular arrays at surfaces », L.Porte et al., Int. J. Nanotechnology 9(3,4,5,6,7), p325-354 (2012).
- « Graphite, graphene on SiC, and graphene nanoribbons: Calculated images with a numerical FM-AFM », F.Castanié, L.Nony, S.Gauthier and X.Bouju, **Beilstein J. of Nanotechnology** 3, p301-311 (2012).
- « *Dipole-driven self-organization of zwitterionic molecules on alkali halide surfaces »*, L.Nony et al., **Beilstein J. of** Nanotechnology 3, p285-293 (2012).
- « Inhomogeneous relaxation of a molecular layer on an insulator due to compressive stress », F.Bocquet, L.Nony, S.C.B.Mannsfeld, V.Oison, R.Pawlak, L.Porte and Ch.Loppacher, **Phys. Rev. Lett.** 108, 206103 (2012).
- « *Image Calculations with a Numerical Frequency-Modulation Atomic Force Microscope »,* F.Castanié, L.Nony, S.Gauthier, and X.Bouju, J. Phys. Chem. C 117, 10492 (2013).
- « Correct height measurements by Kelvin probe force microscopy: Poly(3-dodecylthiophene) on highly oriented pyrolytic graphite », F.Fuchs, B.Grévin, F.Bocquet, L.Nony, and Ch.Loppacher, **Phys. Rev. B** 88, 205423 (2013).
- *« Electrothermally driven high-frequency piezoresistive SiC cantilevers for dynamic atomic force microscopy »,* R.Boubekri, E.Cambril, L.Couraud, L.Bernardi, A.Madouri, M.Portail, T.Chassagne, C.Moisson, M.Zielinski, S.Jiao, J.-F.Michaud, D.Alquier, J.Bouloc, L.Nony, F.Bocquet, Ch.Loppacher, D.Martrou, and S.Gauthier, J. Appl. Phys. 116, 054304 (2014).









List of publications of the « non-contact AFM » team (2008)

- «Molecular design and control over the morphology of self-assembled films on ionic substrates», A.Amrous, F.Bocquet, L.Nony, F.Para, Ch.Loppacher, S.Lamare, F.Palmino, F.Chérioux, D.Z.Gao, F.F.Canova, M.B.Watkins and A.L.Shluger, Adv. Mat. Interf. 1, 1400414 (2014).
- « Supramolecular networks on a silicon surface or on insulators», M.Beyer, Y.Makoudi, S.Lamarre, J.Jeannoutot, F.Palmino, F.Chérioux, A.Amrous, F.Bocquet, L.Nony, F.Para and Ch.Loppacher, Abstracts of papers of the American Chemical Society, 247, 342-COLL (2014).
- « Integration of the RHK R9 to an Omicron VT-AFM », L.Nony, F.Para, F.Bocquet and Ch.Loppacher, <u>http://www.rhk-tech.com/wp-content/uploads/2016/02/R9 Omicron ApplicationNote.pdf</u>, RHK Technology Application Note (2015).
- *« Frequency shift, damping and tunneling current coupling with quartz tuning forks in non-contact atomic force microscopy »,* L.Nony, F.Bocquet, F.Para and Ch.Loppacher, **Phys.Rev.B.** 94, 115421 (2016).
- *« Morphology and growth mechanisms of self-assembled films on insulating substrates: role of molecular flexibility and entropy»,* J.Gaberle, D.Z. Gao, A.L. Shluger, S.Lamare, F.Palmino, F.Cherioux, A.Amrous, F.Bocquet, L.Nony, F.Para, and Ch.Loppacher, **J. Phys. Chem C** 121, 4393-4401 (2017).
- « Non-contact AFM and Differential Reflectance Spectroscopy joint analyzes of bispyrenyl thin films on bulk insulators: relationship between structural and optical properties», F.Bocquet, L.Nony, F.Para, P.Luangprasert, J.-V.Naubron, Ch.Loppacher, T.Leoni, A.Thomas, A.Ranguis, A.d'Aleo, F.Fages, and C.Becker, **Phys.Rev.B** 97, 235434 (2018).
- « *Micrometer-long covalent organic fibres by photo-initiated radical polymerisation on an alkali halide surface »,* F.Para, F.Bocquet, L.Nony, Ch.Loppacher, M.Feron, F.Cherioux, D.Z.Gao, M.Watkins, **Nature Chemistry** (2018)









